

CLAIMS

1. A probe station for probing a test device,
said probe station comprising:

5 (a) a chuck for supporting said test device;

(b) a plurality of electrically conductive
members, each electrically isolated from, and at least
partially enclosing said surface; and

10 (c) a selector member having a plurality of
positions, one said position electrically isolating said
electrically conductive members from each other and
another said position electrically interconnecting one
said conductive member with at least one other said
conductive member.

15 2. The probe station of claim 1 having only
two said conductive members.

3. The probe station of claim 1 including an
outer conductive member at least partially surrounding at
least one other said conductive member.